

<b>Notice of References Cited</b>	Application/Control No. 10/679,293		Applicant(s)/Patent Under Reexamination OH ET AL.	
	Examiner Dennis M. Butler		Art Unit 2115	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0137502	07-2003	Lee, Eun-bae	345/212
*	B	US-2003/0156106	08-2003	Byun, Ho-jin	345/212
*	C	US-6,504,534	01-2003	Takase et al.	345/211
*	D	US-6,223,283	04-2001	Chaiken et al.	713/1
*	E	US-6,178,513	01-2001	Lee, Ji-Young	713/300
*	F	US-5,961,647	10-1999	Kim et al.	713/300
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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